

Geometry-dependent electrostatics near contact lines

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Long-ranged electrostatic interactions in electrolytes modify their contact angles on charged substrates in a scale and geometry dependent manner. For angles measured at scales smaller than the typical Debye screening length, the wetting geometry near the contact line must be explicitly considered. Using variational and asymptotic methods, we derive new transcendental equations for the contact angle that depend on the electrostatic potential only at the three phase contact line. Analytic expressions are found in certain limits and compared with predictions for contact angles measured with lower resolution. An estimate for electrostatic contributions to *line* tension is also given.

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Modern microfluidic and patterning applications call for directed fluid flow and wetting on treated surfaces often exhibiting complex surface chemistry [1, 2, 3, 4]. Mechanisms of differential wetting of small droplets of electrolytes have also been exploited as electrically activated switches and micropumps [5]. In such systems, the effects of surface ionization have been found to be important [1, 4, 6, 7, 8].

Consequently, one often considers two immiscible fluids of dielectric constants ϵ_0, ϵ_1 that partially wets an ionizable, rigid substrate, as shown in Figs. 1. The two liquids, depending on their individual pKa's, will differentially hydrolyze/ionize substrates such as glass. Ionizable surfactants may also be adsorbed, imparting a fixed, relatively uniform surface charge σ at the interfaces. Microscopically, surface tensions γ arise from mismatches in short-ranged molecular interactions (*e.g.* van der Waal's) among the various species. Electrostatic double layers also contribute to surface energies. The application of the classical Young-Dupré (Y-D) equation [9], $\gamma'_{01} \cos \alpha^* \approx \gamma'_{0s} - \gamma'_{1s}$, with electrostatically modified surface energies (*e.g.* $\gamma'_{1s} = \gamma_{1s} + \frac{1}{2}\sigma_1\varphi_1$, where σ_1 and φ_1 are surface charges and potentials in, say, liquid 1 far from the contact point P) is accurate provided the apparent contact angle α^* is measured at a point P^* outside the range κ^{-1} of the electric double layers. However, the screening length κ^{-1} , although typically smaller than the resolution of optical goniometry measurements, can be within the resolution (nanometers) of emerging angle measurement techniques using AFM [10]. Even at lower resolutions, finite-sized double-layer effects may be relevant for contact angle measurements. For example, hydrolysis of pure water gives $\kappa^{-1} \sim 1\mu\text{m}$, while in organic mixtures, with fewer mobile ions, the screening length can be even longer [4]. If the contact angle is measured at P , within the ionic double layers, the simple Y-D equation is not appropriate.

Previous theories that consider surface energy modifications [1, 6, 7, 8, 11, 12, 13], have either assumed microscopic-ranged interactions or infinite-system surface free energy changes (*i.e.* $\gamma \rightarrow \gamma + \frac{1}{2}\sigma\varphi$). Effects of the wedge-like geometry on the intrinsic electrostatics

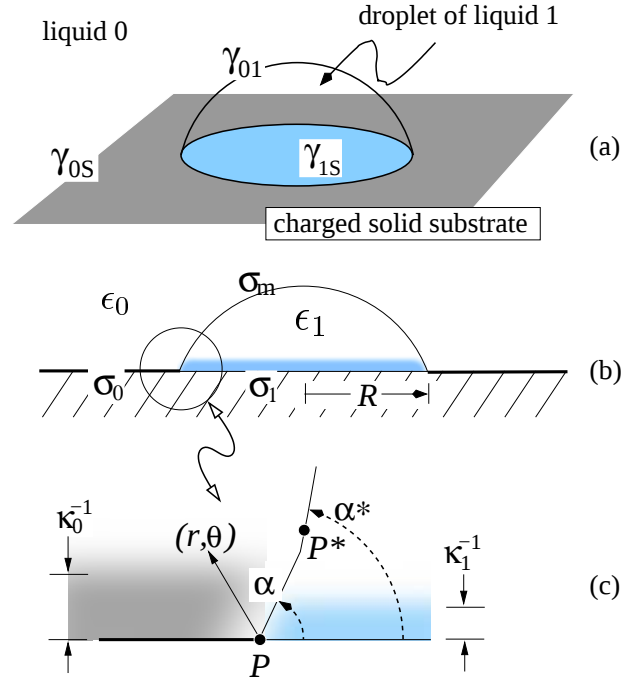


FIG. 1: (a) Two liquids with dielectric constants ϵ_0, ϵ_1 wets a charged substrate. (b) The substrate is ionized and acquires fixed charge densities of σ_0, σ_1 . Charged surfactants can also impart a surface charge σ_m at the fluid-fluid interface. (c) In order to satisfy boundary conditions, the different screening layers deform near the contact point P .

near the contact line have not been considered. In this letter, we derive formulae for the angle¹ at the true three phase contact line in the presence of long-ranged electrostatic interactions. Rich features arise in this most simple and classic problem when geometry is self-consistently

¹ Measured within both double layers, but outside the length scale of other more microscopic interactions.

incorporated. We propose using weak ionic solutions as a system with precisely controllable electrostatics for studying charge contributions to contact angle and line tension forces. Our results are summarized by Eqns. (3), (11), and (16).

The “mechanical” free energy of an axisymmetric liquid droplet of footprint radius R (cf. Figs. 1a,b) in contact with a flat, solid substrate is $G_{mech} = (\gamma_{1s} - \gamma_{0s}) \int d\mathbf{r} + \gamma_{01} \oint d\mathbf{S}_{01} + G_{body}$, where γ are the surface tensions *sans* electrostatic interactions, $d\mathbf{r}$ is the in-plane surface element, $\mathbf{S}$ is the liquid-liquid surface element. The G_{body} term may include gravitational energy, $(\rho_1 - \rho_0)g/2 \int h^2(r)d\mathbf{r}$, and/or Lagrange multipliers to *e.g.* fix droplet volumes of incompressible liquids. The electrostatic free energy for a specified surface charge ensemble, written as a functional of the local electrostatic potential φ is [14]

$$G_{el} = \oint \sigma(\mathbf{S})\varphi(\mathbf{S})d\mathbf{S} - \int d\mathbf{r}dz \left[\frac{\epsilon(\mathbf{r},z)}{8\pi} |\nabla\varphi|^2 + U[\varphi] \right] \quad (1)$$

where $U[\varphi(\mathbf{r})] \equiv \sum_i e\nu_i c_i^\infty (\exp(-\nu_i\varphi(\mathbf{r})) - 1)$ is a term summing the interactions among mobile charged species i , each with valency ν_i and bulk concentration c_i^∞ . We have expressed all energy and length quantities in terms of $k_B T$ and the Bjerrum length $\ell_B = e^2/k_B T$. Variation of $G_{el}[\varphi(\mathbf{r}), \nabla\varphi(\mathbf{r}); h(\mathbf{r}), \nabla h(\mathbf{r})]$ with respect to $\varphi(\mathbf{r})$ for a fixed droplet height function $h(\mathbf{r})$ yields the Poisson-Boltzmann equation with appropriate boundary conditions. Similarly, variation of $G_T = G_{mech} + G_{el}$ with respect to the droplet height $h(\mathbf{r})$ determines the complete shape of the electrolyte droplet via

$$\gamma_{01} \partial_{\mathbf{t}}^2 h_{\perp}(\mathbf{r}) = \left[\frac{\epsilon}{8\pi} |\nabla\varphi|^2 + U[\varphi] \right]_1^0, \quad (2)$$

where $h_{\perp}$ is the deformation normal to the tangent $\mathbf{t}$ relative to a constant slope. Further minimizing the boundary terms in G_T (which are independent of $U[\varphi]$) with respect to the position of the contact point, $\delta G_T(z=0)/\delta R = 0$, yields²

$$\gamma_{01} \cos \alpha = (\gamma_{0s} - \gamma_{1s}) + (\sigma_0 - \sigma_1)\varphi(P; \alpha). \quad (3)$$

The first two terms arise from setting the variations in the boundary terms of G_{mech} to zero and reproduces the Young-Dupré equation. The last term in (3) is a new generalization of the Y-D equation and arises from minimizing the boundary terms of G_{el} . The additional term depends only on the jump in the solid surface charge and the electrostatic potential $\varphi(P)$ at the three

phase contact line P . This potential is found by solving the Poisson-Boltzmann equation $\nabla^2\varphi(\mathbf{r}) = U'[\varphi(\mathbf{r})]$ in the appropriate geometry, subject to boundary conditions. Therefore, $\varphi(P)$ will depend parametrically on the droplet shape (and hence the contact angle α) near P . Equation (3) is *exact* provided the electrostatic energy is given by G_{el} , and gives an implicit formula for predicting the contact angle α .

In the following, we compute $\varphi(P; \alpha)$ in the linearized limit ($U[\varphi] \approx \kappa^2\varphi^2/2$), valid for $e\varphi(\mathbf{r})/k_B T \ll 1$, by solving Kelvin’s (*aka* Debye-Hückel) equation in each of the two fluid domains depicted in Figs. 1:

$$\Delta\varphi_j = \kappa_j^2\varphi_j(r, \theta) \quad \text{in fluid } j = 0, 1. \quad (4)$$

The screening lengths $\kappa_j^{-1} \equiv \left(\frac{4\pi e}{\epsilon_j} \sum_i \nu_i^2 c_i^\infty \right)^{-1/2}$ are assumed much smaller than the dimensions of the droplet. Furthermore, neglecting gravity, (2) shows that $h_{\perp}(\mathbf{r})$ varies (relative to a perfect wedge) over a length scale $L_h \sim \sqrt{\gamma_{01}/(\kappa\varphi^2(P))}$. Provided $L_h \gg \kappa^{-1}$, the wedge is distorted only in the region where $\varphi \approx 0$, sufficiently beyond the contact point P to be appreciably influenced by electrostatic interactions. Thus, $\varphi(P)$ will be computed using a perfect wedge geometry. The boundary conditions associated with (4) in 2D wedge domains are

$$\begin{aligned} \epsilon_1 \partial_{\theta} \varphi_1(r, 0) &= 4\pi r \sigma_1 \\ \epsilon_0 \partial_{\theta} \varphi_0(r, \pi) &= -4\pi r \sigma_0 \\ \varphi_0(r, \alpha) - \varphi_1(r, \alpha) &= 0 \\ \epsilon_0 \partial_{\theta} \varphi_0(r, \alpha) - \epsilon_1 \partial_{\theta} \varphi_1(r, \alpha) &= 4\pi r \sigma_m. \end{aligned} \quad (5)$$

The linear problem defined above is related to the classic problem of wave scattering from a wedge, which remains a substantial mathematical and computational challenge [15]. The problem is best attacked using the Lebedev-Kantorovich (LK) integral transform

$$f_j(x, \theta) = \int_0^\infty \varphi_j(r, \theta) K_{ix}(\kappa_j r) \frac{dr}{r} \equiv \mathcal{L}_{\kappa_j} \varphi_j, \quad (6)$$

and its inverse

$$\varphi_j(r, \theta) = \frac{2}{\pi^2} \int_0^\infty f(x, \theta) K_{ix}(\kappa_j r) x \text{sh}(\pi x) dx \equiv \mathcal{L}_{\kappa_j}^{-1} f_j. \quad (7)$$

If the contact angle can be measured sufficiently close the contact point (closer than κ_j^{-1} , such as in [10]), the potential $\varphi(\kappa r \rightarrow P)$ can be easily expressed in terms of its transform $f(x, \theta)$. We will henceforth scale distance as $\xi = \kappa_0 r$ and reinsert κ_0 back into the final, quoted results. Asymptotic analysis of the integral representation $K_{ix}(\xi) = (1/2) \int_{-\infty}^\infty \exp[-\xi \text{cht} + ixt] dt$ yields $\lim_{\xi \rightarrow 0} K_{ix}(\xi) \sim (\sin xt^*)/x$, where $t^* = \lim_{\xi \rightarrow 0} \cosh^{-1}(1/\xi) = \infty$. The limit $\lim_{t^* \rightarrow \infty} (\sin xt^*)/x = \pi\delta(x)$, implies

² The liquid-liquid surface tension γ_{01} may also change due to electrocapillarity, but this can be modification measured independently using *e.g.* pendant drop methods.

$$\lim_{\xi \rightarrow 0} \varphi(\xi, \theta) = \lim_{x \rightarrow 0} [x^2 f(x, \theta)]. \quad (8)$$

We find analytic expressions for $\varphi(r, \theta)$ in two limiting cases that illustrate the full range of behaviors: $\kappa_0 \approx \kappa_1$, and $\kappa_1 \gg \kappa_0$. In the former case of nearly identical screening lengths unequal dielectric constants $\epsilon_0 \neq \epsilon_1$ provide a nontrivial electric field jump across $\theta = \alpha$. In the latter case, we will choose a small screening length (e.g., high salt) in region 1 without loss of generality. In both cases, the potential can be expanded in the power series $\varphi_j(r, \theta) = \sum_{n=0}^{\infty} \mu^{(n)}(\epsilon) \varphi_j^{(n)}(r, \theta)$, where ϵ is a small parameter that depends on the ratio of screening lengths and the relevant regime:

$\kappa_1 \approx \kappa_0$ *limit* - In this limit, $\mu^{(n)}(\epsilon) = \epsilon^n$ and $\epsilon \equiv (\kappa_1/\kappa_0)^2 - 1$. At each order ϵ^n the governing equations are $\Delta \varphi_0^{(n)} = \varphi_0^{(n)}$ for $\theta \geq \alpha$, and $\Delta \varphi_1^{(n)} = \varphi_1^{(n)} + \varphi_1^{(n-1)}$ for $\theta \leq \alpha$. Upon applying $\mathcal{L}_1$ to the n^{th} order Debye-Hückel equations, $\partial_\theta^2 f_0^{(n)} = x^2 f_0^{(n)}(x, \theta)$ and $\partial_\theta^2 f_1^{(n)} = x^2 f_1^{(n)}(x, \theta) = g^{(n-1)}(x, \theta)$ where $g^{(n-1)}(x, \theta) \equiv \mathcal{L}_1 \varphi^{(n-1)} r^2 (1 - \delta_{n,0})$.

Similarly, the transformed boundary conditions at each order become $\partial_\theta f_0^{(n)}(x, \theta = \pi) = (2\pi^2 \sigma_0 / \epsilon_0) \text{sech}(\pi x / 2) \delta_{n,0}$, $\partial_\theta f_1^{(n)}(x, \theta = 0) = -(2\pi^2 \sigma_1 / \epsilon_1) \text{sech}(\pi x / 2) \delta_{n,0}$, and $\epsilon_1 \partial_\theta f_1^{(n)}(x, \theta = \alpha) - \epsilon_0 \partial_\theta f_0^{(n)}(x, \theta = \alpha) = 2\pi^2 \sigma_m \text{sech}(\pi x / 2) \delta_{n,0}$. Since $f_1^{(0)}(x, \theta)$ obeys a homogeneous equation, it is determined explicitly. The equations for $f_1^{(n)}(x, \theta)$ can be solved with the appropriate Green function $G(x, \theta, \theta') = -\text{ch } x \theta_{<} \text{ch } x \theta_{>} - \alpha / (x \text{sh } x \alpha)$, $\partial_{\theta'} G(x, \theta, \theta' = 0, \alpha) = 0$, where $\theta_{<}(\theta_{>})$ is the smaller (larger) of θ, θ' . We obtained, after some algebra, an integral equation for $f_1(x, \theta)$. The first iteration of this integral equation yields

$$\epsilon f_1^{(1)}(x, \theta) = \epsilon \int_0^\infty dx' \int_0^\alpha d\theta' H(\theta, \theta'; x, x') f_1^{(0)}(x', \theta') \quad (9)$$

where

$$H(\theta, \theta'; x, x') \equiv \frac{(\epsilon_1/4)G(\theta, \theta'; x)(x^2 - x'^2)x' \text{sh} \pi x' \text{sh} x \alpha}{(\epsilon_1 \text{sh} x \alpha + \epsilon_0 \text{ch} x \theta \text{th} x(\pi - \alpha)) \text{sh} \frac{\pi}{2}(x + x') \text{sh} \frac{\pi}{2}(x - x')}. \quad (10)$$

Upon integrating (9) over θ' , and using $f_1(x, \theta) \approx f_1^{(0)}(x, \theta) + \epsilon f_1^{(1)}(x, \theta)$ in (8), we find $\varphi(P; \alpha)$ up to $O(\epsilon)$:

$$\varphi(P; \alpha) \sim \frac{2\pi^2/\kappa_0}{\epsilon_1 \alpha + \epsilon_0(\pi - \alpha)} \left[(\sigma_0 + \sigma_1 + \sigma_m) + \epsilon (\sigma_0 S_0(\alpha; \lambda) + \sigma_1 S_1(\alpha; \lambda) + \sigma_m S_m(\alpha; \lambda)) + O(\epsilon^2) \right]. \quad (11)$$

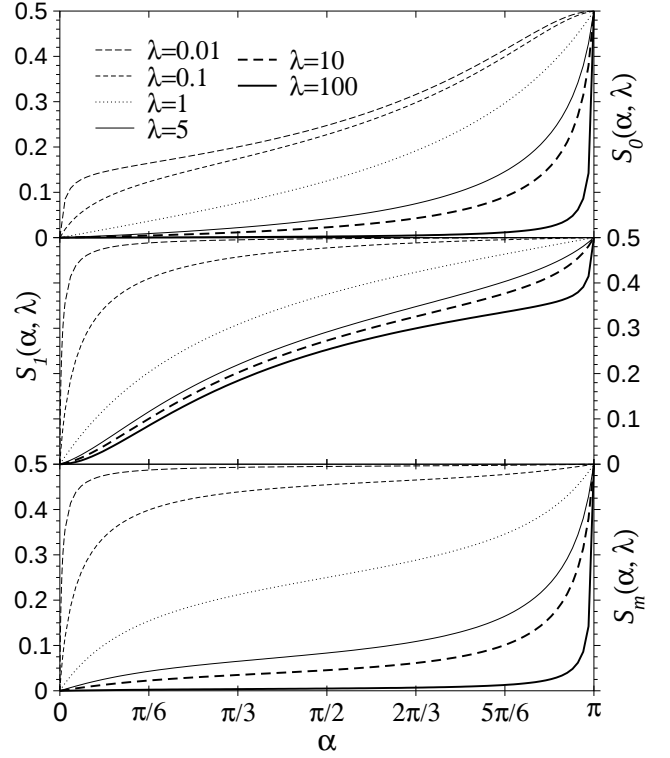


FIG. 2: The functions $S_i(\alpha; \lambda = \epsilon_0/\epsilon_1)$ representing the order $\epsilon = \kappa_1^2/\kappa_0^2 - 1$ contributions to $\varphi(\alpha; P)$ (cf. Equation (11)).

The first (zeroth order) term arises from $\lim_{x \rightarrow 0} x^2 f_1^{(0)}$, while the $O(\epsilon)$ terms can be expressed as single α -dependent integrals $S_i(\alpha; \lambda)$. The functions S_i are plotted *vs.* α in Fig. 2 for various dielectric mismatches $\epsilon_0/\epsilon_1 \equiv \lambda$. The term that remains when $\kappa_0 = \kappa_1$ and that multiplies all higher order terms in ϵ is an effective angular average over the dielectrics ϵ_0, ϵ_1 . This dominant term is *qualitatively different* from that arising from simple surface tension renormalization $\gamma \rightarrow \gamma + \frac{1}{2}\sigma\varphi = \gamma + 2\pi\sigma^2/(\epsilon\kappa)$. The higher order terms S_i are determined with κ_1 relative to κ_0 and thus have their major effect when $\alpha \approx \pi$ as more of the volume is occupied by electrolyte of inverse screening length κ_1 . For larger(smaller) $\lambda = \epsilon_0/\epsilon_1$, $S_0(S_1)$ varies more significantly over a smaller range of angles α , reflecting the importance of the charged surface on the lower dielectric slice. The effects of the liquid-liquid surface charge are symmetric with the interchange $\alpha \rightarrow \pi - \alpha$, $\epsilon_0, \kappa_0, \sigma_0 \rightarrow \epsilon_1, \kappa_1, \sigma_1$ as expected.

$\kappa_0/\kappa_1 \rightarrow 0$ *limit* - In the limit $\kappa_1 \gg \kappa_0$ (4) become $\Delta \varphi_0 = \varphi_0$ and $\Delta \varphi_1 = \epsilon^{-2} \varphi_1$, where $\epsilon \equiv \kappa_0/\kappa_1$. Due to the strong screening in region 1, the potential under the surface wet by liquid 1 vanishes as $\sim \sigma_1(\epsilon_1 \kappa_1)^{-1}$. The first iteration makes the approximation $\varphi_1^{(0)}(r, \theta) = f_1^{(0)} \approx 0$. However, as a result of continuity of the potential at $\theta = \alpha$, and finite κ_0 and σ_0 ,

$$f_0^{(0)}(x, \theta) = \frac{2\pi^2\sigma_0}{\epsilon_0\kappa_0x} \frac{\text{sh}x(\alpha - \theta)}{\text{ch}x(\pi - \alpha)\text{ch}(\pi x/2)}. \quad (12)$$

Thus, $\varphi_0(\theta > \alpha) = \mathcal{L}_1^{-1}f_0^{(0)} \neq 0$. The first nonzero term in $\varphi(P)$ arises from using (12) in the jump condition at $\theta = \alpha$:

$$\partial_\theta f_1(x, \alpha) - \frac{\epsilon_0}{\epsilon_1} \mathcal{L}_\varepsilon \mathcal{L}_1^{-1} \partial_\theta f_0^{(0)}(x', \alpha) = \varepsilon \left(\frac{2\pi^2\sigma_m}{\epsilon_1\kappa_0\text{ch}(\pi x/2)} \right). \quad (13)$$

Upon expanding $K_{ix}(\xi)$ about its dominant contribution at small ξ in the operator $\mathcal{L}_1^{-1}$ and performing the integration over ξ ,

$$\begin{aligned} \mathcal{L}_\varepsilon \mathcal{L}_1^{-1} \partial_\theta f_0^{(0)}(x', \alpha) &= \frac{\pi\sigma_0}{\epsilon_0\kappa_0} \sum_{n=0}^{\infty} \frac{\varepsilon^{2n}}{n!} \times \\ \text{Im} \int_0^\infty &\frac{x'\Gamma\left(n - \frac{i}{2}(x+x')\right)\Gamma\left(n + \frac{i}{2}(x-x')\right)e^{-ix'\ln\varepsilon}}{\text{ch}(\pi x'/2)\text{ch}x'(\pi - \alpha)\Gamma(n+1-ix')} dx' \end{aligned} \quad (14)$$

The contour integral (14) can be performed exactly to find the two lowest order terms in ε (for $n=0$, $\mu^{(1)}(\varepsilon) = \varepsilon^{\pi/(2\pi-2\alpha)}$ and $\mu^{(2)}(\varepsilon) = \varepsilon$) that must be considered. Using (8), our final result is

$$\varphi(P; \varepsilon/\alpha \rightarrow 0) \sim \frac{2\pi^2(\sigma_0 T_0(\alpha; \varepsilon) + \sigma_m \varepsilon)}{\alpha \epsilon_1 \kappa_0} + O\left(\varepsilon^{\frac{\pi}{2\pi-2\alpha}}, \varepsilon^2\right), \quad (15)$$

where

$$T_0(\alpha; \varepsilon) \equiv \frac{\pi\Gamma^2\left(\frac{\pi}{4(\pi-\alpha)}\right)\varepsilon^{\pi/(2\pi-2\alpha)}}{4(\pi-\alpha)^2 \cos\left(\frac{\pi^2}{4(\pi-\alpha)}\right)\Gamma\left(\frac{3\pi-2\alpha}{2\pi-2\alpha}\right)} - \frac{\varepsilon}{\cos\alpha} \quad (16)$$

is plotted in Fig. 3 for various values of ε .

The $\kappa_0/\kappa_1 \rightarrow 0$ analysis fails for small α , when the fully screened approximation breaks down as the interface approaches the σ_1 -charged solid substrate. The correction to the potential is independent of σ_1 since it is screened out by a large κ_1 . However, the jump condition across $\theta = \alpha$ preserves an ϵ_1 dependence.

We have explicitly incorporated the geometric dependence of long-ranged electrostatic effects by deriving implicit equations for the contact angle valid for $R, L_h \sim (\epsilon/\sigma)\sqrt{\kappa\gamma_{01}} \gg \kappa^{-1}$. Our results show that for large mismatch in screening lengths, the potential at the contact point is proportional to the larger screening length κ_0^{-1} but varies as an α -dependent power of the mismatch κ_0/κ_1 . In the $\kappa \approx \kappa_1$ case, the zeroth order contribution to the potential can yield a nonnegligible effect: For $\kappa \approx 50\text{nm}$, $\epsilon_0 = 20$, $\epsilon_1 = 80$, $\sigma_0 - \sigma_1 \approx 0.1$, $\sigma_0, \sigma_1 \sim O(1)$, the zeroth order correction to the surface energy varies from $\sim 1.5 - 0.4k_B T/\ell_B^2$ as α varies from

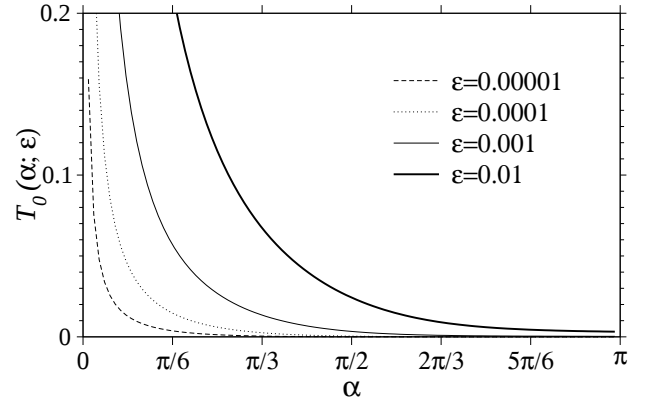


FIG. 3: The function $T_0(\alpha; \varepsilon)$ (Eqn. (3)) that gives the σ_0 -proportional term for the potential (Eqn. (15)) in the $\varepsilon = \kappa_0/\kappa_1 \rightarrow 0$ limit.

0 to π . Since one $k_B T/\ell_B^2 \simeq 8$ dyne/cm, the implicit α dependence should be observable as long as the contact angle can be measured at a distance within 50nm of P . Such measurements are possible using AFM techniques [10]. Geometry-dependent electrostatics may also be an origin for the discrepancy between standard theory and measurements performed at low salt concentrations when screening length are long [8]. Even when the apparent contact angle cannot be measured within a screening length of P , our results may provide a basis by which to better understand dynamic phenomena. Since contact line pinning can occur at a length scale smaller than $|P - P^*|$, the dynamics of the contact line may be better correlated with the true contact angle α rather than α^* .

Note that $S_i(\alpha; \lambda)$ and $T_0(\alpha; \varepsilon)$, when used in (11) allow for the possibility of *two* solutions for α . The physical value for α will be determined by the minimum energy solution that needs to be determined by the full solution of the shape along $P - P^*$. Therefore, in cases where two roots for α are possible, we expect the minimum energy solution to be the one closest to α^* . Our results also imply that dramatic effects on wettability ($\alpha \approx 0, \pi$) can be induced by small changes in the physical parameters.

In our strictly 2D analyses, the only bounded solution when $\kappa_0 = \sigma_0 = 0$ (*e.g.* air) is $\varphi(P; \alpha) = 0$. However, an asymptotic analysis for the large radius ($R \gg L_h, \kappa^{-1}$) limit is possible. The correction term to the Y-D equation resulting from such an analysis is proportional to $\tau \propto \sigma_1^2/(\kappa_1^2 R)$ times an α -dependent factor, and defines the *line tension* [10, 12, 16] arising from electrostatics. These electrostatic forces giving rise to line tension may be sufficiently long-ranged to be experimentally determined through a measurement of α . Ionic strength may thus provide a controllable parameter with which to measure the elusive, and controversial, line tension of wetting [16].

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